

STP50NE10

N-channel 100V - 0.021Ω - 50A TO-220 STripFET™ Power MOSFET

General features

Туре	V _{DSS}	R _{DS(on)}	I _D
STP50NE10	100V	<0.027Ω	50A

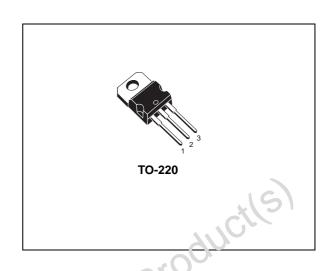
- Exceptional high dv/dt capability
- 100% avalanche tested
- Low gate charge at 100 °C
- Application oriented characterization

Description

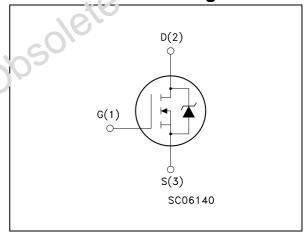
This Power MOSFET is the latest development of STMicroelectronis unique "Single Feature SizeTM" strip-based process. The resulting transistor shows extremely high packing density for low onresistance, rugged avalanche characteristics and less critical alignment steps therefore a remarkable manufacturing reproducibility.

Applications

■ Switching application



Internal schematic diagram



Order codes

Part number	number Marking Package		Packaging
STP50NE10	P50NE10	TO-220	Tube

Contents STP50NE10

Contents

1	Electrical ratings 3
2	Electrical characteristics4
	2.1 Electrical characteristics (curves)
3	Test circuit 8
4	Package mechanical data 9
5	Revision history11
Olosol	Revision history

STP50NE10 Electrical ratings

1 Electrical ratings

Table 1. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (V _{GS} = 0)	100	V
V _{DGR}	Drain-gate voltage ($R_{GS} = 20KΩ$)	100	V
V _{GS}	Gate-source voltage	± 20	V
I _D	I_D Drain current (continuous) at $T_C = 25^{\circ}C$ 50		Α
I _D	Drain current (continuous) at T _C =100°C	35	Α
I _{DM} ⁽¹⁾	Drain current (pulsed)	200	Α
P _{TOT}	Total dissipation at T _C = 25°C	180	W
	Derating factor	1	W/°C
dv/dt ⁽²⁾	Peak diode recovery voltage slope	6	V/ns
T _J T _{stg}	Operating junction temperature Storage temperature	175 -65 to 175	°C

^{1.} Pulse width limited by safe operating area

Table 2. Thermal data

R _{thj-case}	Thermal resistance junction-case Max	1	°C/W
R _{thj-a}	Thermal resistance junction-ambient Max	62.5	°C/W
Rthc-sink	Thermal resistance case-sink typ	0.5	°C/W
T _I	Maximum lead temperature for soldering purpose	300	°C

Table 3. Avalanche characteristics

Symbol	Parameter	Value	Unit
lar	Avalanche current, repetitive or not-repetitive (pulse width limited by Tj Max)	50	Α
E _{AS}	Single pulse avalanche energy (starting Tj=25°C, Id=lar, Vdd=50V)	300	mJ

^{2.} I_{SD} \$0A, di/dt \$00A/ μ s, $V_{DD} \le V_{(BR)DSS}$, $T_j \le T_{JMAX}$

Electrical characteristics STP50NE10

Electrical characteristics 2

(T_{CASE}=25°C unless otherwise specified)

On/off states Table 4.

Symbol	Parameter	Test condictions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source breakdown voltage	$I_D = 250 \ \mu A, \ V_{GS} = 0$	100			V
I _{DSS}	Zero gate voltage drain current (V _{GS} = 0)	V_{DS} = Max rating, V_{DS} = Max rating @125°C			1 10	μA μA
I _{GSS}	Gate body leakage current (V _{DS} = 0)	V _{GS} = ±20V			± 100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	3	4	٧
R _{DS(on)}	Static drain-source on resistance	V _{GS} = 10V, I _D = 25A		0.021	0.027	Ω

Table 5. **Dynamic**

	Symbol	Parameter	Test condictions	Min.	Тур.	Max.	Unit
	g _{fs} ⁽¹⁾	Forward transconductance	$V_{DS} > ID(on) \times RDS(on)max$, $I_D = 25A$	20	35		S
	C _{iss} C _{oss} C _{rss}	Input capacitance Output capacitance Reverse transfer capacitance	V_{DS} =25V, f=1 MHz, V_{GS} =0		4350 5000 175	6000 675 238	pF pF pF
	t _{d(on)}	Turn-on Delay Time Rise Time	V_{DD} = 50V, I_D = 25A, R_G = 4.7 Ω , V_{GS} = 10V (see Figure 12)		25 100	34 135	ns ns
	Q _g Q _{gs} Q _{gd}	Total gate charge Gate-source charge Gate-drain charge	V _{DD} =80V, I _D = 50A V _{GS} =10V		123 24 47	166	nC nC nC
Obsole	1 Pulcod:	oulse duration=300μs, duty cycle	1.5%				

Table 6. Source drain diode

Symbol	Parameter	Test condictions	Min	Тур.	Max	Unit
I _{SD}	Source-drain current				6	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)				24	Α
V _{SD} ⁽²⁾	Forward on voltage	I _{SD} =50A, V _{GS} =0			1.5	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	I _{SD} =50A, di/dt = 100A/μs, V _{DD} =30V, Tj=150°C (see Figure 14)		155 700 9		ns μC A

- 1. Pulse width limited by safe operating area
- 2. Pulsed: pulse duration=300µs, duty cycle 1.5%

 Obsolete Product(S)

 Obsolete Product(S)

Electrical characteristics STP50NE10

2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

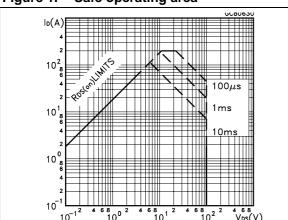


Figure 2. Thermal impedance

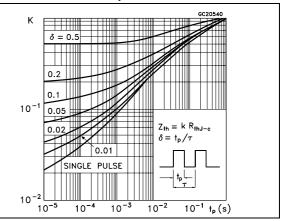
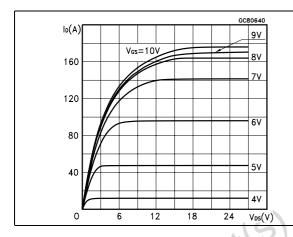


Figure 3. Output characterisics

Figure 4. Transfer characteristics



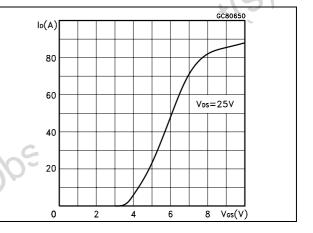
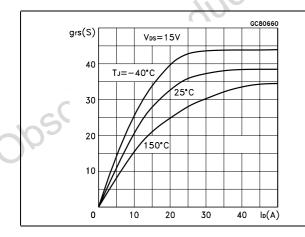
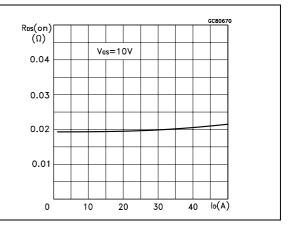


Figure 5. Transconductance

Figure 6. Static drain-source on resistance





Vgs(V) f=1MHz Vgs=0V V_{DS}=48V I_D=50A 9.6 8 7.2 6 Ciss 2.4 0 120 Q₉(nC) 30 60 90

Figure 7. Gate charge vs gate-source voltage Figure 8. Capacitance variations

Normalized gate threshold voltage Figure 9. vs temperature

Vos(V) 0 10 20 30 40

Vgs(th) (norm) V_{DS}=V_{GS} I_D=250µA 1.2 1.0 0.8 0.6 0.4 100 TJ(°C)

Figure 10. Normalized on resistance vs temperature

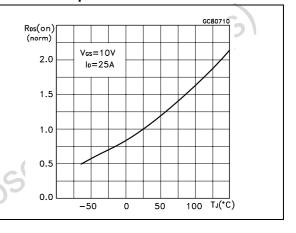
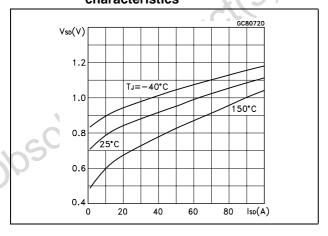


Figure 11. Source-drain diode forward characteristics



Test circuit STP50NE10

3 Test circuit

Figure 12. Switching times test circuit for resistive load

Figure 13. Gate charge test circuit

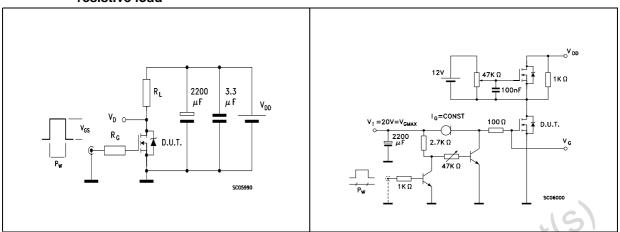


Figure 14. Test circuit for inductive load switching and diode recovery times

Figure 15. Unclamped Inductive load test circuit

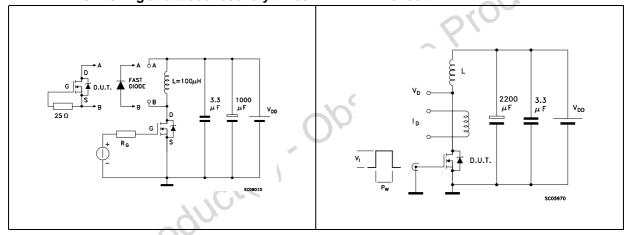
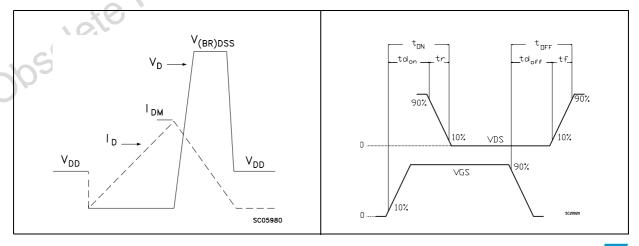


Figure 16. Unclamped inductive waveform

Figure 17. Switching time waveform



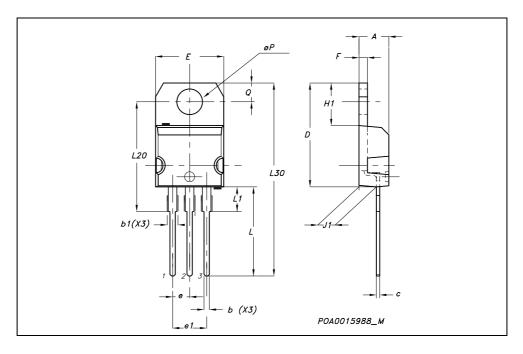
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: www.st.com

Obsolete Product(s). Obsolete Product(s)

TO-220 MECHANICAL DATA

DIM	mm.				inch	
DIM.	MIN.	TYP	MAX.	MIN.	TYP.	MAX.
Α	4.40		4.60	0.173		0.181
b	0.61		0.88	0.024		0.034
b1	1.15		1.70	0.045		0.066
С	0.49		0.70	0.019		0.027
D	15.25		15.75	0.60		0.620
Е	10		10.40	0.393		0.409
е	2.40		2.70	0.094		0.106
e1	4.95		5.15	0.194		0.202
F	1.23		1.32	0.048		0.052
H1	6.20		6.60	0.244		0.256
J1	2.40		2.72	0.094		0.107
L	13		14	0.511		0.551
L1	3.50		3.93	0.137		0.154
L20		16.40			0.645	
L30		28.90			1.137	
øΡ	3.75		3.85	0.147		0.151
Q	2.65		2.95	0.104		0.116



Obsole

STP50NE10 Revision history

5 Revision history

Table 7. Revision history

Date	Revision	Changes
09-Sep-2004	7	Complete version
10-Aug-2006	8	New template, no content change

Obsolete Product(s). Obsolete Product(s)

Please Read Carefully:

Information in this document is provided solely in connection with ST products. STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, modifications or improvements, to this document, and the products and services described herein at any time, without notice.

All ST products are sold pursuant to ST's terms and conditions of sale.

Purchasers are solely responsible for the choice, selection and use of the ST products and services described herein, and ST assumes no liability whatsoever relating to the choice, selection or use of the ST products and services described herein.

No license, express or implied, by estoppel or otherwise, to any intellectual property rights is granted under this document. If any part of this document refers to any third party products or services it shall not be deemed a license grant by ST for the use of such third party products or services, or any intellectual property contained therein or considered as a warranty covering the use in any manner whatsoever of such third party products or services or any intellectual property contained therein.

UNLESS OTHERWISE SET FORTH IN ST'S TERMS AND CONDITIONS OF SALE ST DISCLAIMS ANY EXPRESS OR IMPLIED WARRANTY WITH RESPECT TO THE USE AND/OR SALE OF ST PRODUCTS INCLUDING WITHOUT LIMITATION IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE (AND THEIR EQUIVALENTS UNDER THE LAWS OF ANY JURISDICTION), OR INFRINGEMENT OF ANY PATENT, COPYRIGHT OR OTHER INTELLECTUAL PROPERTY RIGHT.

UNLESS EXPRESSLY APPROVED IN WRITING BY AN AUTHORIZED ST REPRESENTATIVE, ST PRODUCTS ARE NOT RECOMMENDED, AUTHORIZED OR WARRANTED FOR USE IN MILITARY, AIR CRAFT, SPACE, LIFE SAVING, OR LIFE SUSTAINING APPLICATIONS, NOR IN PRODUCTS OR SYSTEMS WHERE FAILURE OR MALFUNCTION MAY RESULT IN PERSONAL INJURY, DEATH, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE. ST PRODUCTS WHICH ARE NOT SPECIFIED AS "AUTOMOTIVE GRADE" MAY ONLY BE USED IN AUTOMOTIVE APPLICATIONS AT USER'S OWN RISK.

Resale of ST products with provisions different from the statements and/or technical features set forth in this document shall immediately void any warranty granted by ST for the ST product or service described herein and shall not create or extend in any manner whatsoever, any liability of ST.

ST and the ST logo are trademarks or registered trademarks of ST in various countries.

Information in this document supersedes and replaces all information previously supplied.

The ST logo is a registered trademark of STMicroelectronics. All other names are the property of their respective owners.

© 2006 STMicroelectronics - All rights reserved

STMicroelectronics group of companies

Australia - Belgium - Brazil - Canada - China - Czech Republic - Finland - France - Germany - Hong Kong - India - Israel - Italy - Japan - Malaysia - Malta - Morocco - Singapore - Spain - Sweden - Switzerland - United Kingdom - United States of America

www.st.com